

# RFD3055, RFD3055SM, RFP3055

Data Sheet

### January 2002

### 12A, 60V, 0.150 Ohm, N-Channel Power MOSFETs

These are N-Channel enhancement mode silicon gate power field effect transistors. They are advanced power MOSFETs designed, tested, and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA49082.

### **Ordering Information**

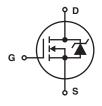
PART NUMBER	PACKAGE	BRAND
RFD3055	TO-251AA	FD3055
RFD3055SM	TO-252AA	FD3055
RFP3055	TO-220AB	FP3055

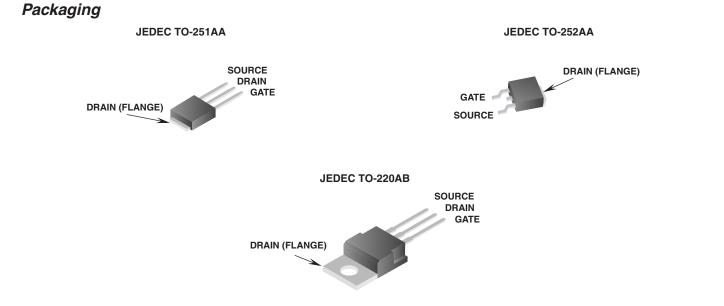
NOTE: When ordering, use the entire part number. Add the suffix 9A, to obtain the TO-252AA variant in tape and reel, i.e. RFD3055SM9A.

### Features

- 12A, 60V
- r<sub>DS(ON)</sub> = 0.150Ω
- Temperature Compensating PSPICE<sup>®</sup> Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- 175<sup>o</sup>C Operating Temperature
- Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

### Symbol





#### Absolute Maximum Ratings $T_{C} = 25^{\circ}C$ , Unless Otherwise Specified

	RFD3055, RFD3055SM, RFP3055	UNITS
Drain to Source Voltage (Note 1)	60	V
Drain to Gate Voltage (R <sub>GS</sub> = 20KΩ) (Note 1)V <sub>DGR</sub>	60	V
Gate to Source VoltageV <sub>GS</sub>	±20	V
Continuous Drain Current	12	А
Pulsed Drain Current (Note 3)	Refer to Peak Current Curve	А
Single Pulse Avalanche Rating (Figures 14, 15) I <sub>AS</sub>	Refer to UIS Curve	
Power DissipationPD	53	W
Linear Derating Factor	0.357	W/ <sup>o</sup> C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s	300	°C
Package Body for 10s, See Techbrief 334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTE:

1.  $T_J = 25^{\circ}C$  to  $150^{\circ}C$ .

PARAMETER	SYMBOL	TEST CONDITIONS		MIN	ТҮР	MAX	UNITS
Drain to Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V (Figure 11)		60	-	-	V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$ (Figure 10)		2	-	4	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = Rated BV <sub>DSS</sub> , $V_{GS}$ = 0V		-	-	1	μΑ
		$T_{C} = 125^{\circ}C, V_{DS}$	= 0.8 x Rated BV <sub>DSS</sub>	-	-	25	μA
Gate to Source Leakage Current	I <sub>GSS</sub>	$V_{GS} = \pm 20V$		-	-	100	nA
Drain to Source On Resistance	r <sub>DS(ON)</sub>	I <sub>D</sub> = 12A, V <sub>GS</sub> = 10V (Figure 9) (Note 2)		-	-	0.150	Ω
Turn-On Time	ton	$V_{DD} = 30V, I_D = 12A$		-	-	40	ns
Turn-On Delay Time	t <sub>d(ON)</sub>	R <sub>L</sub> = 2.5Ω, V <sub>GS</sub> = R <sub>G</sub> = 10Ω	-	7	-	ns	
Rise Time	t <sub>r</sub>	(Figure 13)	-	21	-	ns	
Turn-Off Delay Time	t <sub>d(OFF)</sub>		-	16	-	ns	
Fall Time	t <sub>f</sub>	-		-	10	-	ns
Turn-Off Time	tOFF			-	-	40	ns
Total Gate Charge	Q <sub>g(TOT)</sub>	$\label{eq:VGS} \begin{array}{l} V_{GS} = 0 \text{ to } 20V \\ V_{GS} = 0 \text{ to } 10V \\ V_{GS} = 0 \text{ to } 10V \\ V_{GS} = 0 \text{ to } 2V \end{array} \begin{array}{l} V_{DD} = 48V, I_D = 12A, \\ R_L = 4\Omega, \\ I_g(REF) = 0.24mA \\ (Figure 13) \end{array}$		-	19	23	nC
Gate Charge at 10V	Q <sub>g(10)</sub>			-	10	12	nC
Threshold Gate Charge	Q <sub>g(TH)</sub>			-	0.6	0.8	nC
Input Capacitance	C <sub>ISS</sub>	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1MHz (Figure 12)		-	300	-	pF
Output Capacitance	C <sub>OSS</sub>			-	100	-	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			-	30	-	pF
Thermal Resistance Junction to Case	R <sub>0JC</sub>			-	-	2.8	°C/W
Thermal Resistance Junction to Ambient	R <sub>0JA</sub>	TO-251 and TO-252		-	-	100	°C/W
		TO-220		-	-	62.5	°C/W

#### Electrical Specifications 25°C Unless Otherwise Specified

### Source to Drain Diode Specifications

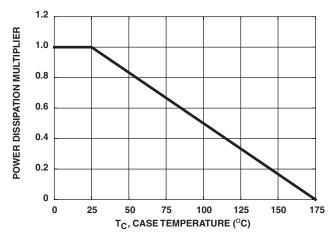
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	ТҮР	MAX	UNITS
Source to Drain Diode Voltage	V <sub>SD</sub>	I <sub>SD</sub> = 12A	-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	$I_{SD}$ = 12A, dI <sub>SD</sub> /dt = 100A/µs	-	-	100	ns

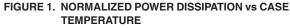
NOTES:

2. Pulse Test: Pulse Width  $\leq$  300ms, Duty Cycle  $\leq$  2%.

3. Repetitive Rating: Pulse Width limited by max junction temperature. See Transient Thermal Impedance Curve (Figure 3) and Peak Current Capability Curve (Figure 5).

### Typical Performance Curves Unless Otherwise Specified





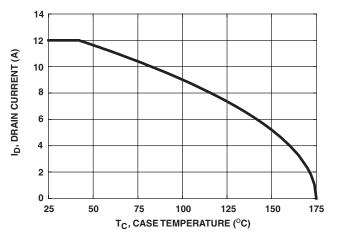
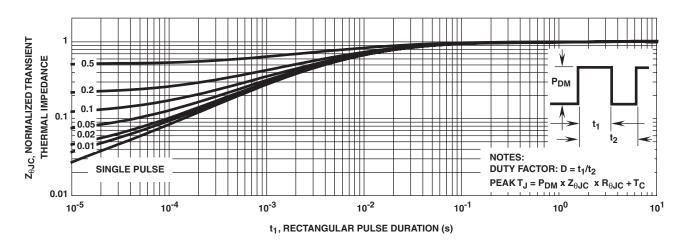
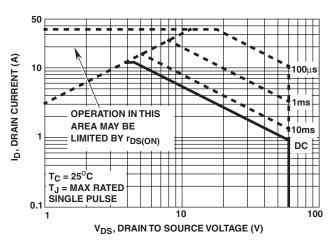


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE









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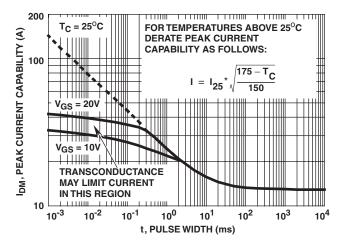
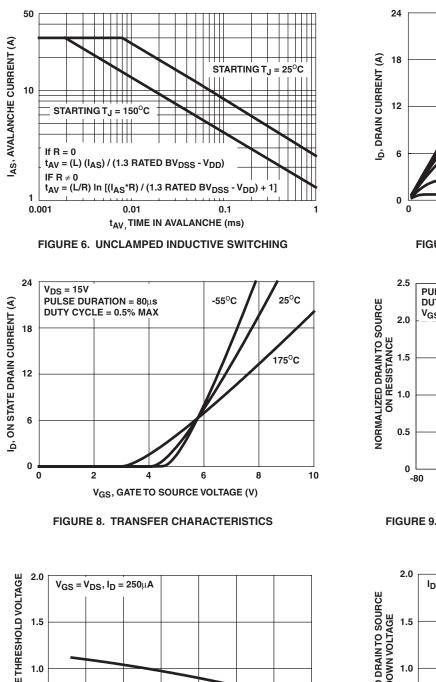


FIGURE 5. PEAK CURRENT CAPABILITY

## Typical Performance Curves Unless Otherwise Specified (Continued)



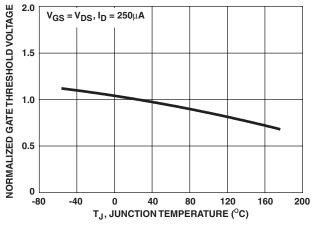
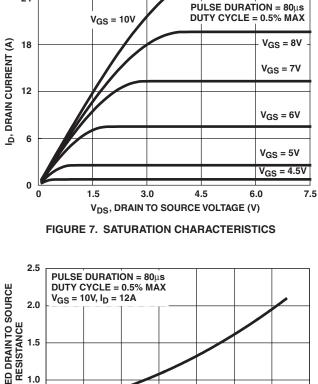
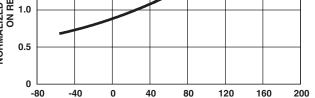


FIGURE 10. NORMALIZED GATE THRESHOLD VOLTAGE vs TEMPERATURE





TJ, JUNCTION TEMPERATURE (°C)

FIGURE 9. NORMALIZED DRAIN TO SOURCE ON **RESISTANCE vs JUNCTION TEMPERATURE** 

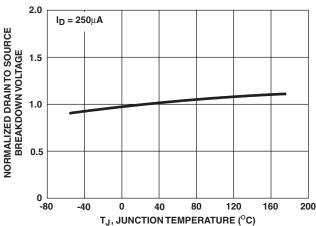


FIGURE 11. NORMALIZED DRAIN TO SOURCE BREAKDOWN **VOLTAGE vs TEMPERATURE** 

### Typical Performance Curves Unless Otherwise Specified (Continued)

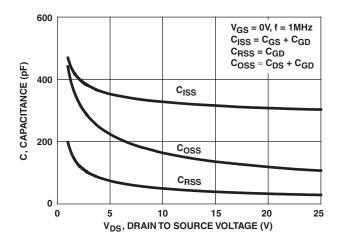
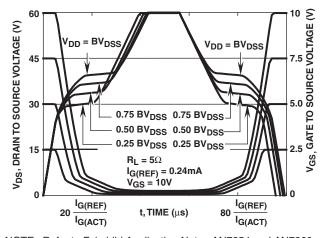
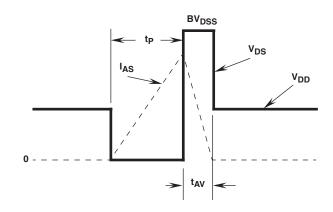


FIGURE 12. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Fairchild Application Notes AN7254 and AN7260. FIGURE 13. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT



#### FIGURE 15. UNCLAMPED ENERGY WAVEFORMS

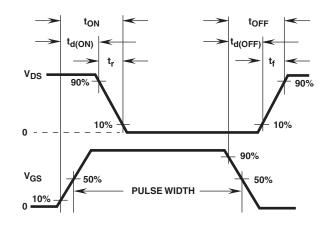


FIGURE 17. RESISTIVE SWITCHING WAVEFORMS

#### Test Circuits and Waveforms

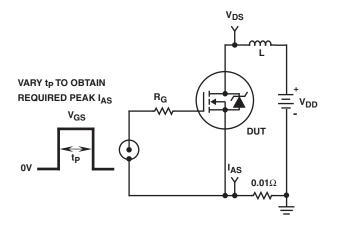


FIGURE 14. UNCLAMPED ENERGY TEST CIRCUIT

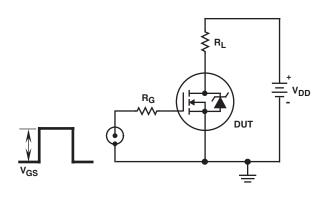
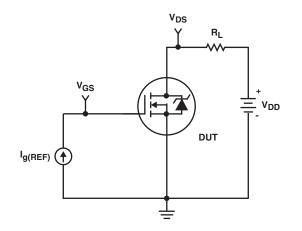


FIGURE 16. SWITCHING TIME TEST CIRCUIT

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# Test Circuits and Waveforms (Continued)



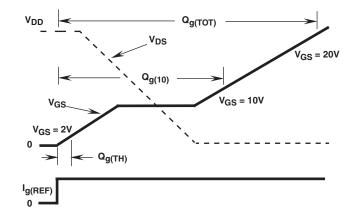


FIGURE 18. GATE CHARGE TEST CIRCUIT

FIGURE 19. GATE CHARGE WAVEFORMS

DPI CAP

5

### PSPICE Electrical Model

.SUBCKT RFP3055 213: rev 10/26/93

CA 12 8 0.540e-9 CB 15 14 0.540e-9 CIN 6 8 0.300e-9

DBODY 7 5 DBDMOD DBREAK 5 11 DBKMOD DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 67.9 EDS 148581 EGS 138681 ESG 6 10 6 8 1 EVTO 20 6 18 8 1

IT 8 17 1

LDRAIN 2 5 1e-9 LGATE 1 9 4.61e-9 LSOURCE 3 7 4.61e-9

MOS1 16 6 8 8 MOSMOD M=0.99 MOS2 16 21 8 8 MOSMOD M=0.01

RBREAK 17 18 RBKMOD 1 RDRAIN 50 16 RDSMOD 1e-4 RGATE 9 20 7.23 RIN 6 8 1e9 RSCL1 5 51 RSLVCMOD 1e-6 RSCL2 5 50 1e3 RSOURCE 8 7 RDSMOD 108e-3 RVTO 18 19 RVTOMOD 1

S1A 6 12 13 8 S1AMOD S1B 13 12 13 8 S1BMOD S2A 6 15 14 13 S2AMOD S2B 13 15 14 13 S2BMOD

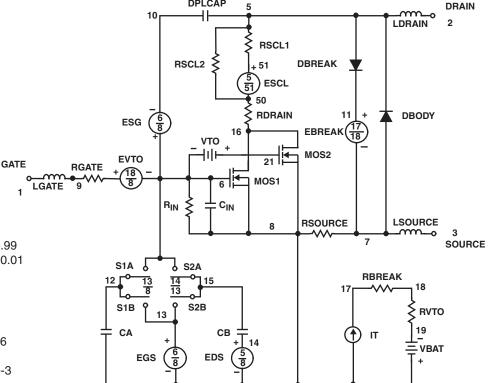
VBAT 8 19 DC 1 VTO 21 6 0.5

ESCL 51 50 VALUE={(V(5,51)/ABS(V(5,51)))\*(PWR(V(5,51)\*1e6/30,6.5))}

.MODEL DBDMOD D (IS=4.33e-14 RS=2.78e-2 TRS1=1.10e-3 TRS2=5.19e-6 CJO=3.94e-10 TT=7.63e-8) .MODEL DBKMOD D (RS=0.676 TRS1=1.94e-3 TRS2=-1.09e-6) .MODEL DPLCAPMOD D (CJO=0.238e-9 IS=1e-30 N=10) .MODEL MOSMOD NMOS (VTO=4.078 KP=12 IS=1e-30 N=10 TOX=1 L=1u W=1u) .MODEL RBKMOD RES (TC1=1.06e-3 TC2=-1.92e-6) .MODEL RDSMOD RES (TC1=5.03e-3 TC2=1.53e-5) .MODEL RSLVCMOD RES (TC1=2.2e-3 TC2=-5e-6) .MODEL RVTOMOD RES (TC1=-5.02e-3 TC2=-9.16e-6) .MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-6.5 VOFF=-3.5) .MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-3.5 VOFF=-6.5) .MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.50 VOFF=2.50) .MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=2.50 VOFF=-2.50)

.ENDS

NOTE: For further discussion of the PSPICE model consult A New PSPICE Sub-Circuit for the Power MOSFet Featuring Global Temperature Options; authored by William J. Hepp and C. Frank Wheatley.



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